Notice of References Cited Application/Control No. 10/553,132 Examiner DEREK S. CHAPEL Applicant(s)/Patent Under Reexamination HESLINE, RAYMOND Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0113055	06-2003	Zhao et al.	385/16
*	В	US-2003/0020989	01-2003	Liu et al.	359/161
*	C	US-2003/0147136	08-2003	Pan et al.	359/484
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Η	US-			
	_	US-			
	7	US-			
	K	US-			
	L_	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.